



仿真
新
时代

2017 ANSYS 用户技术大会

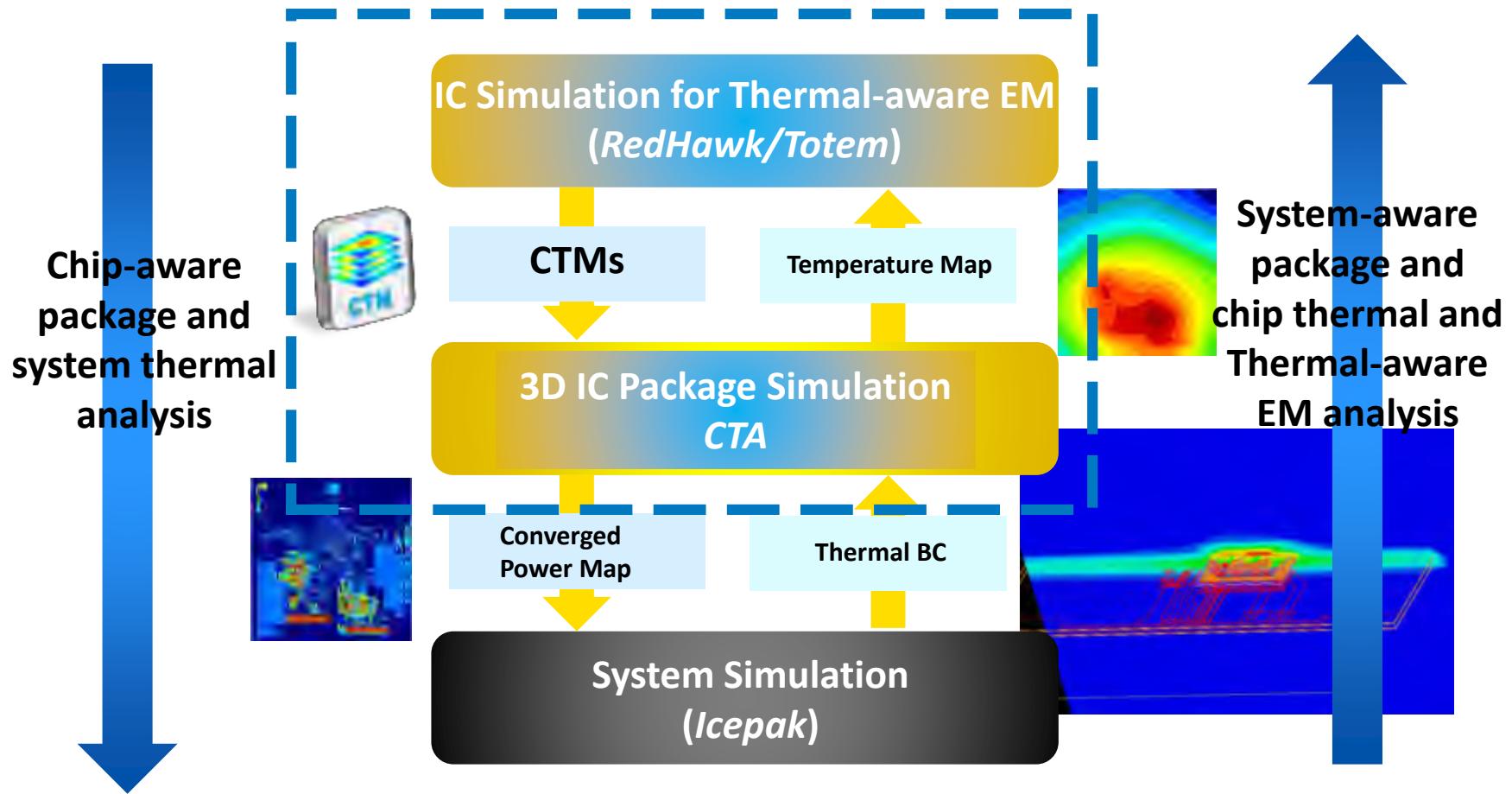
中国·烟台

Chip Package System (CPS) Thermal Integrity Co-Analysis

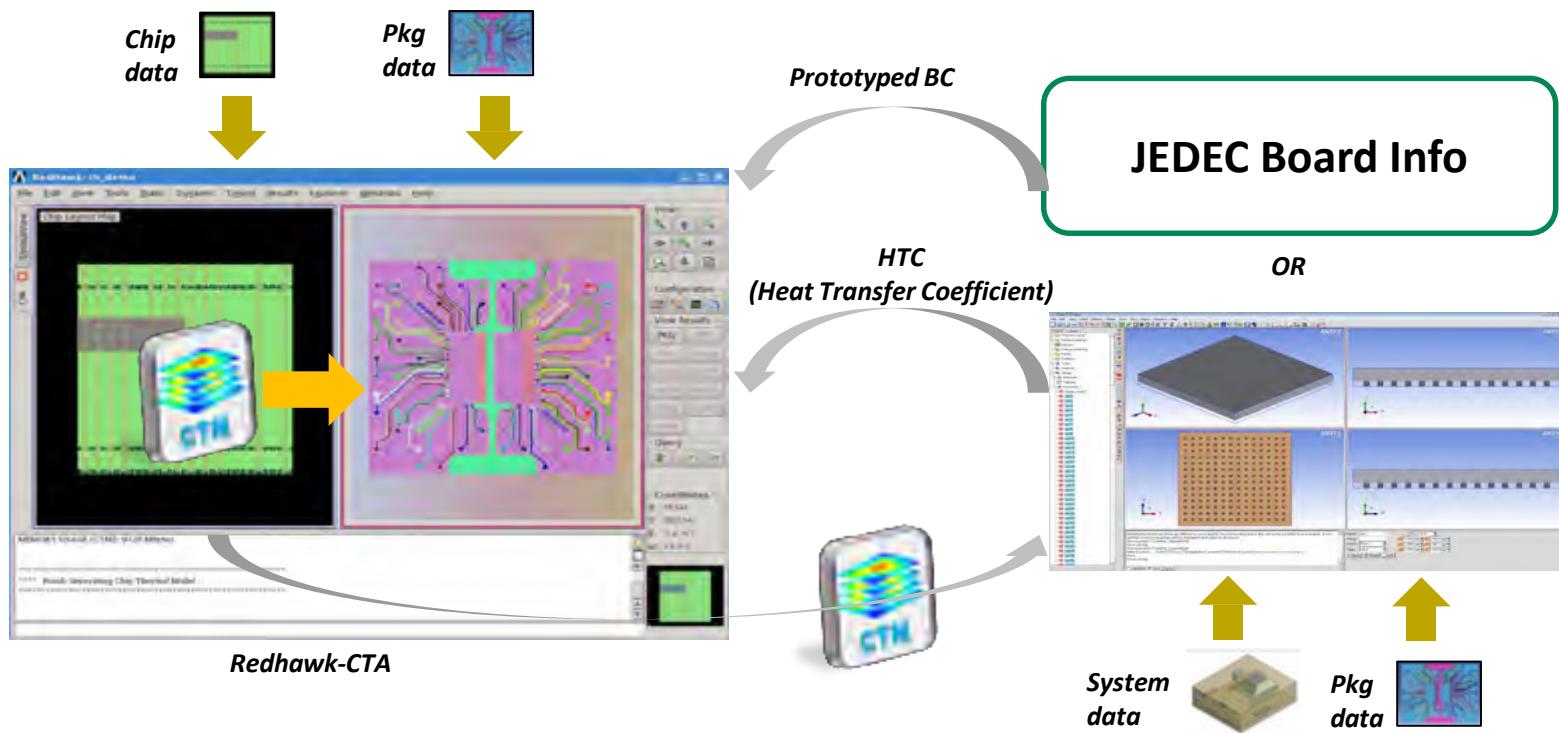
尹国丽 / Principal Product Specialist

Ansys

Chip-Package-System Thermal Integrity Solution



Chip & Board Aware Package Level Thermal Analysis



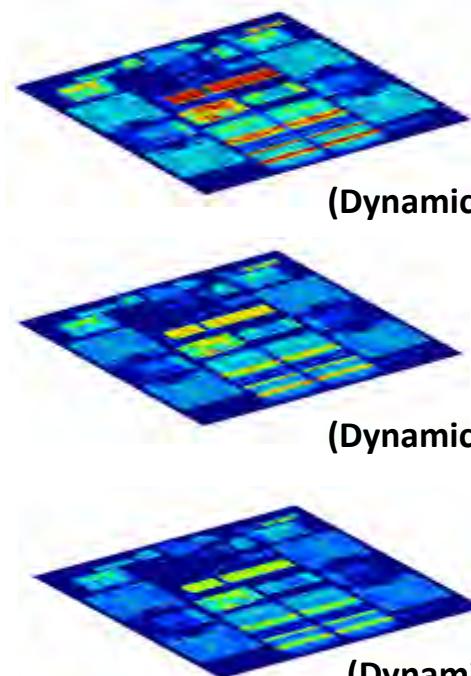
- JEDEC board is widely used for easy package level analysis when info about system is not ready or explicit

Chip Thermal Model (CTM) from RH/Totem

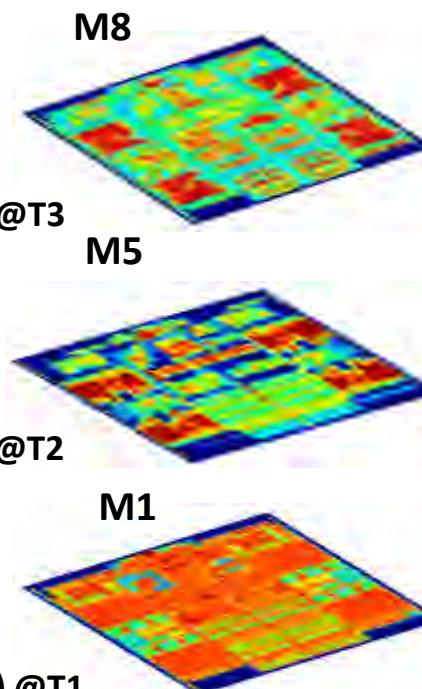
Layer stackup

Power (T)

□ 19: TOP_LAYER
□ 18: Metal8
□ 17: Via7
□ 16: Metal7
□ 15: Via6
□ 14: Metal6
□ 13: Via5
□ 12: Metal5
□ 11: Via4
□ 10: Metal4
□ 9: Via3
□ 8: Metal3
□ 7: Via2
□ 6: Metal2
□ 5: Via1
□ 4: Metal1
■ 3: device_2
□ 2: device_1
□ 1: Substrate



Metal Distribution



CTM content

- Temp-dependent tile-based power density maps
- Per layer metal density map
- Block Power File (separate input)
 - OD and power info

Configuration File(GSR) Setting for Thermal Analysis

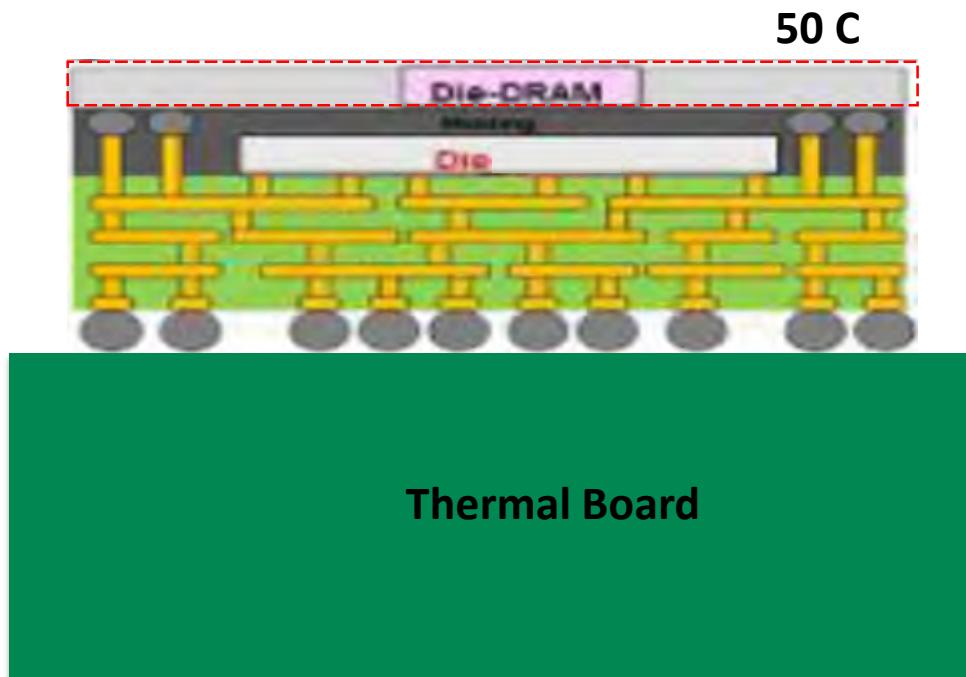
- Specify Package Design and Result Directory

```
CPA_FILES {  
    PACKAGE      ./design.mcm  
    MODEL        ./adsCTA  
}
```

- Must-have Option

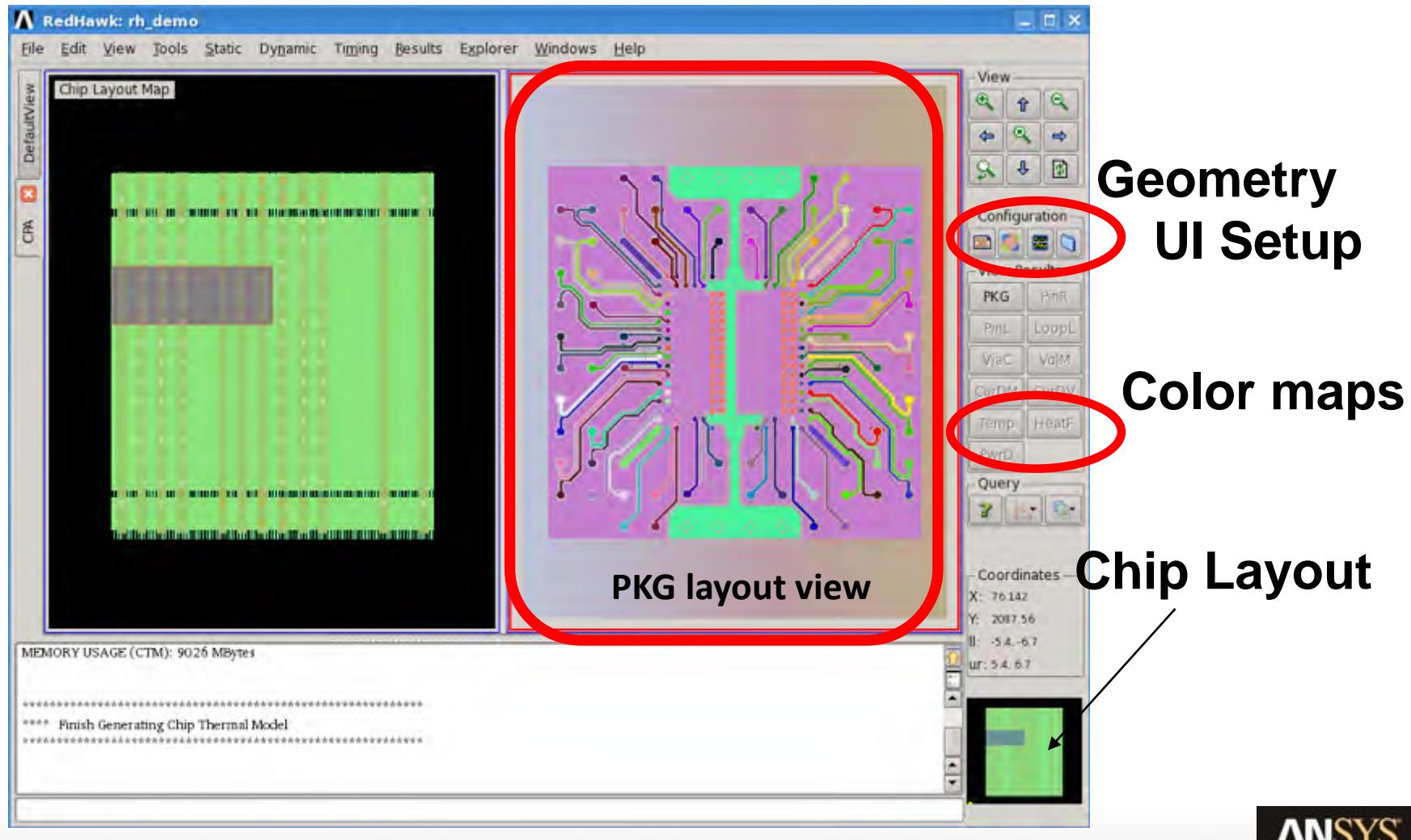
```
THERMAL_ANALYSIS 1
```

Test Design Example: POP Design

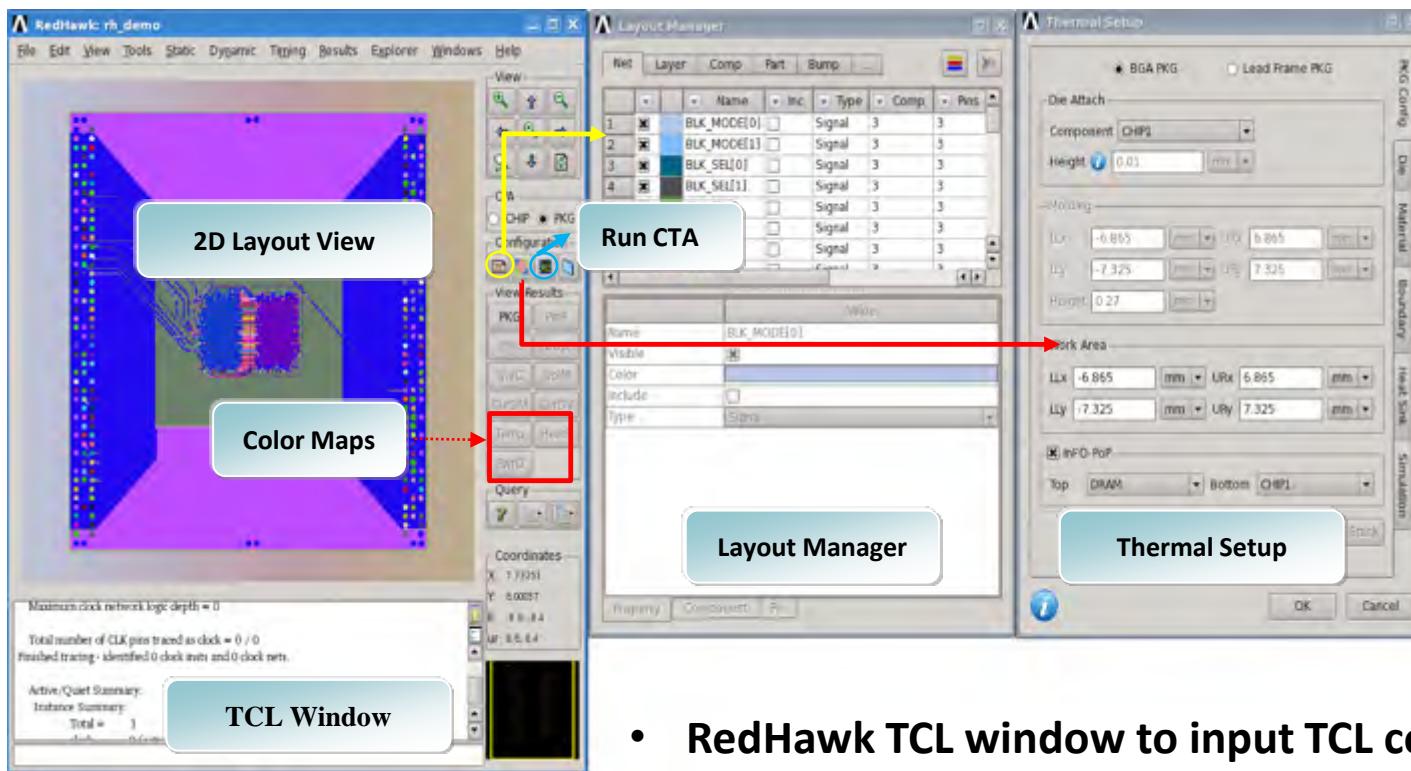


- DRAM + Die + Interposer/Package + Thermal Board
- Prescribed temperature of 50C on DRAM
- CTM power maps on Die (from RH)

Invoke RedHawk/Totem-CTA

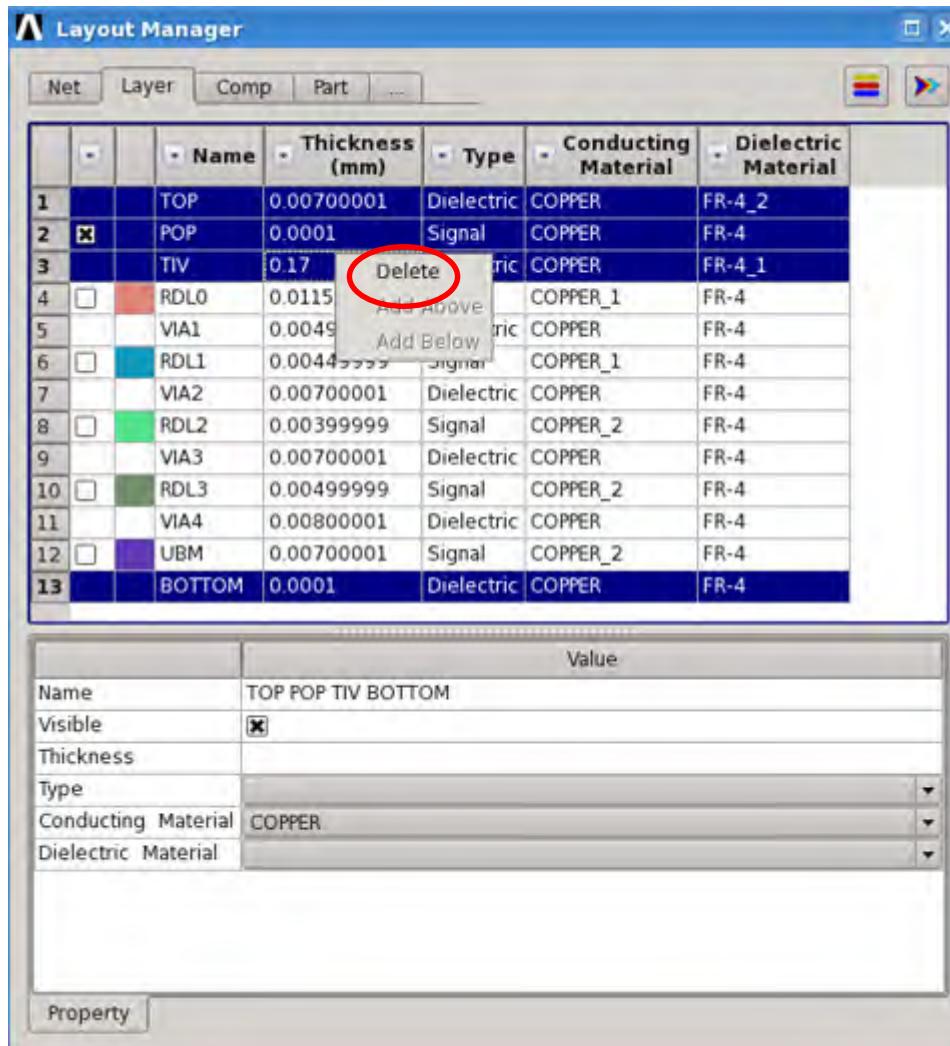


Key Functions for Thermal Analysis



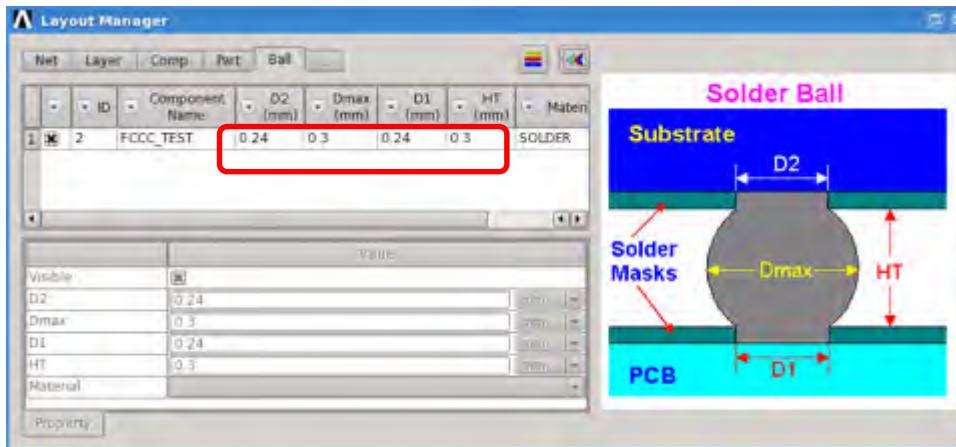
- **RedHawk TCL window to input TCL commands**
- **Layout Manager for layout editing**
- **Thermal Setup dialog for all CTA setup**
- **Color Contours to Display Results**

Design Setup through Layout Manager

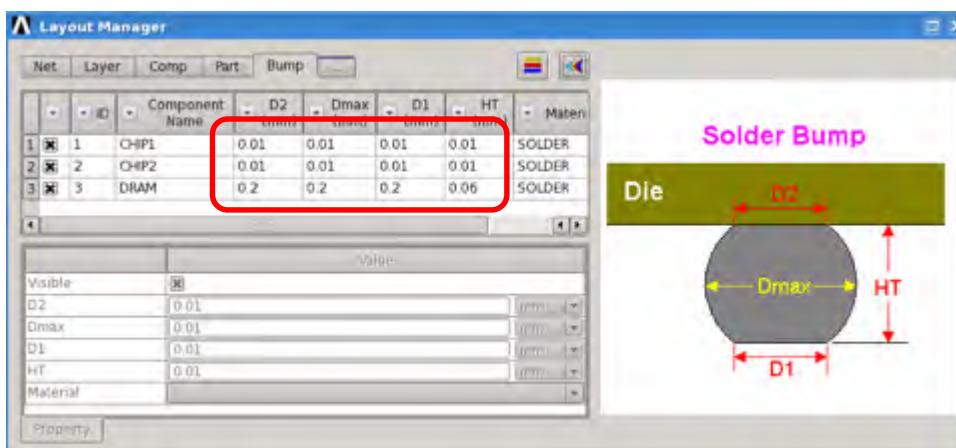


- Set thickness, layer type conductive/dielectric material of target design
- Remove unnecessary layer info
- Various setting for design optimization through what-if analysis

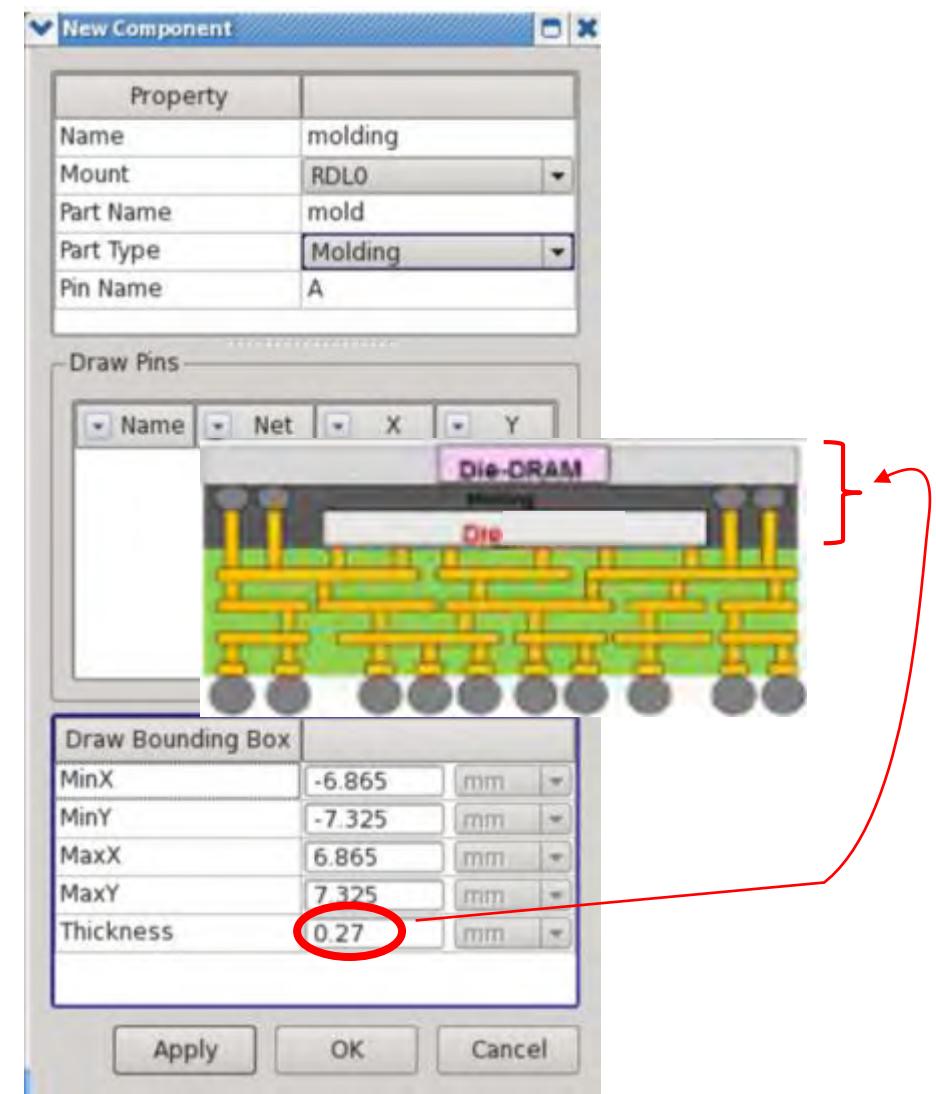
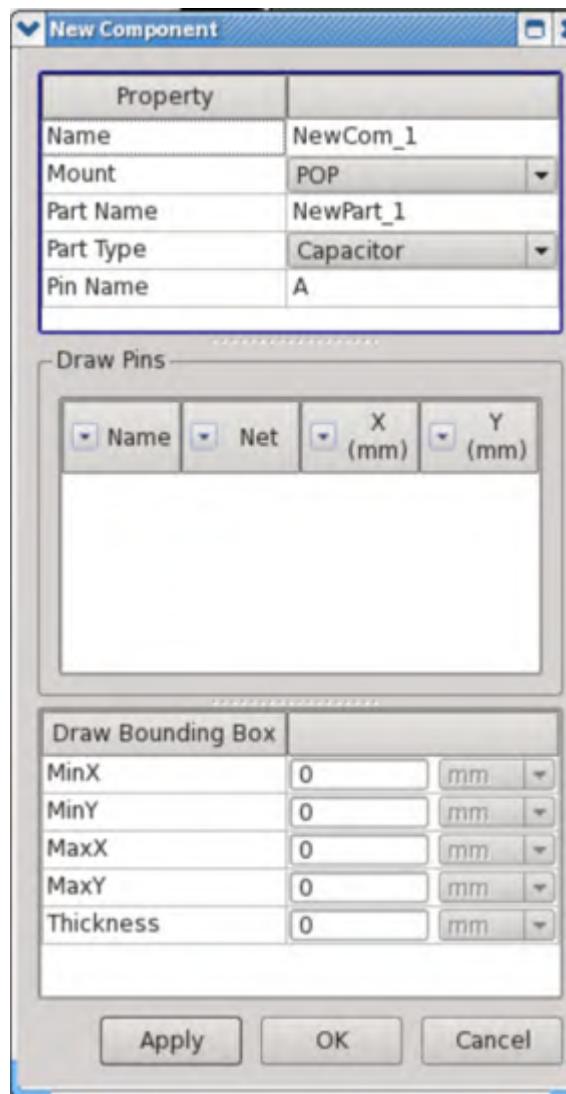
Specify Info for Bump/Ball



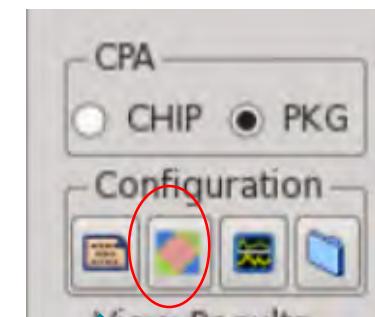
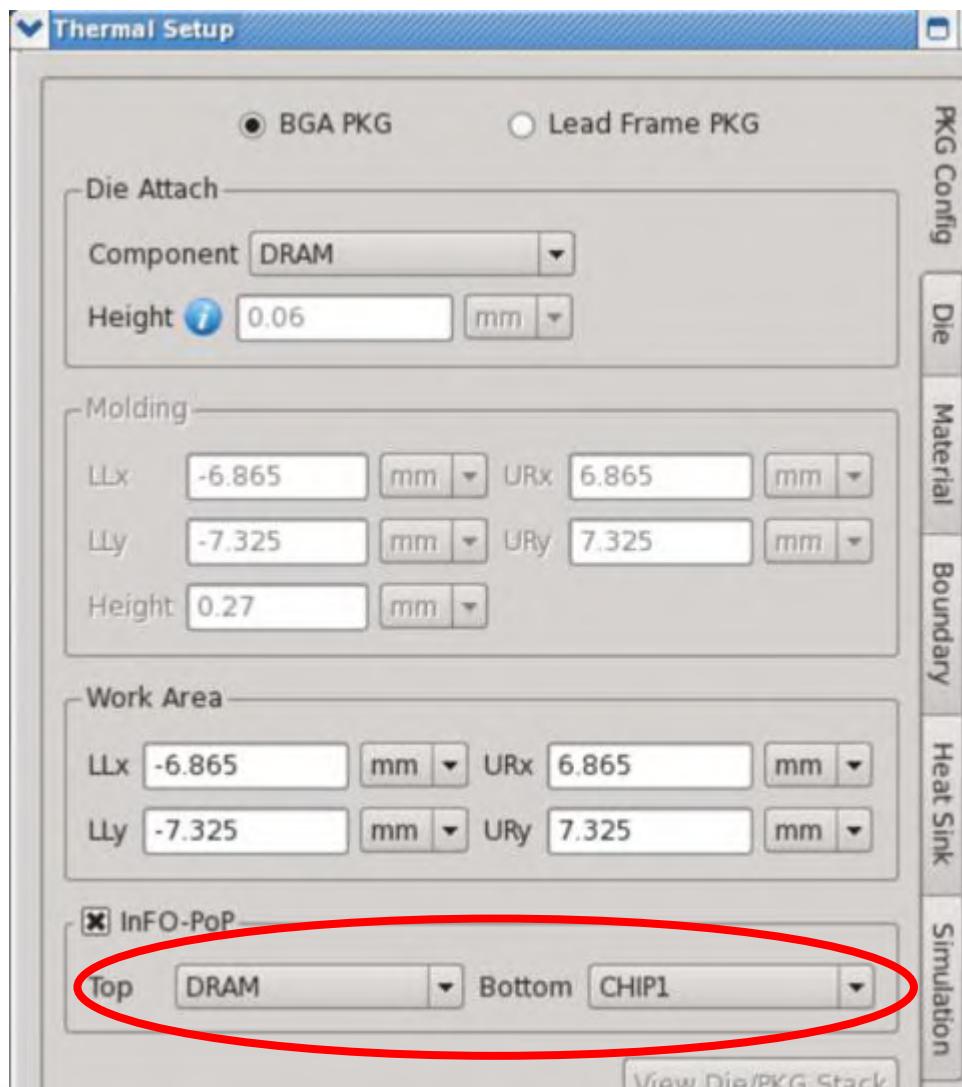
- Change Bump/Ball to practical values
- Bump/Ball are crucial info related to heat transference



Add Molding to enclose Package and Die

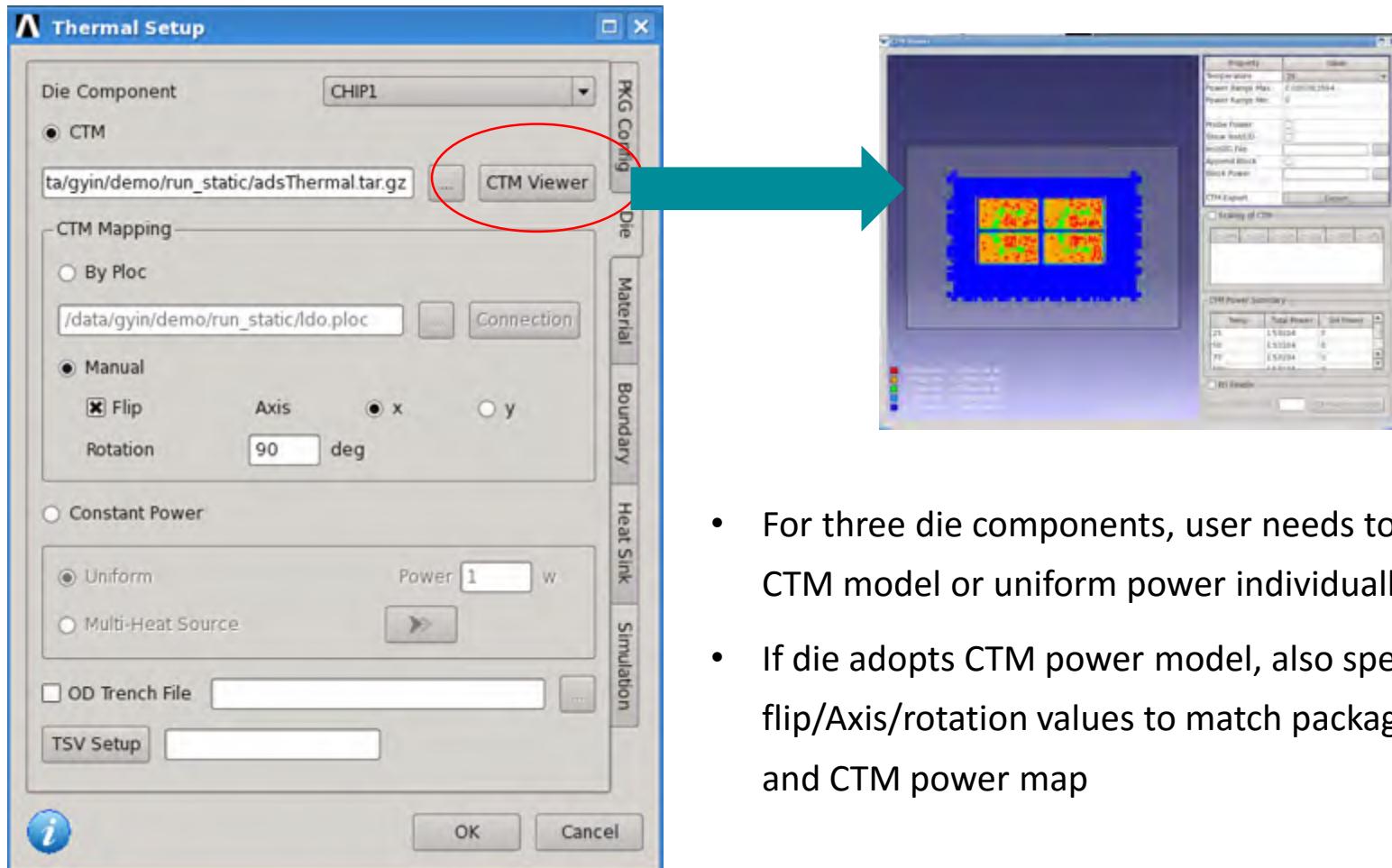


Set Up Package Configuration



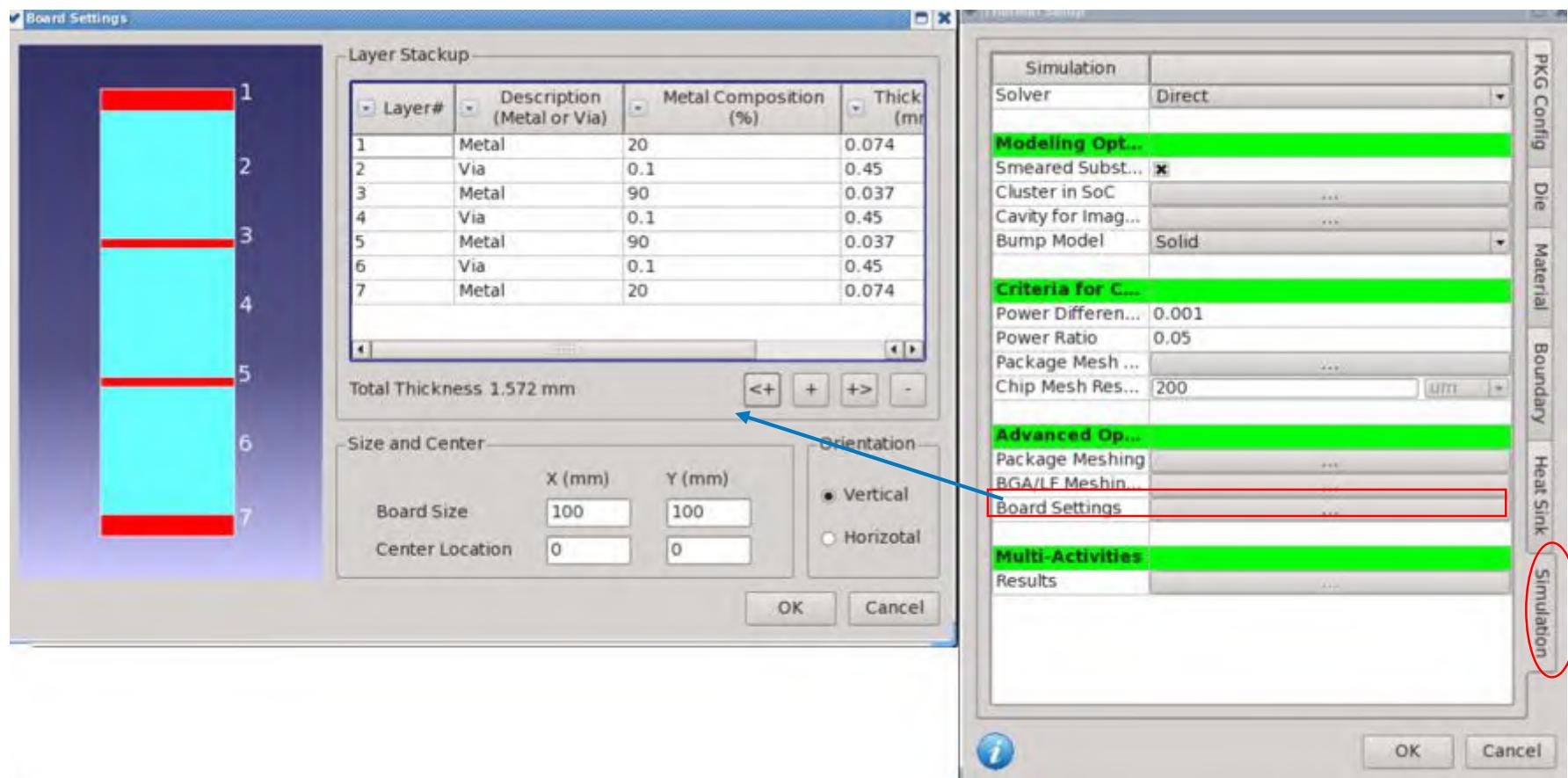
- Stackup of DRAM on Die, i.e., DRAM on top of CHIP1

Heat Source Define: CTM, OD, Power Map

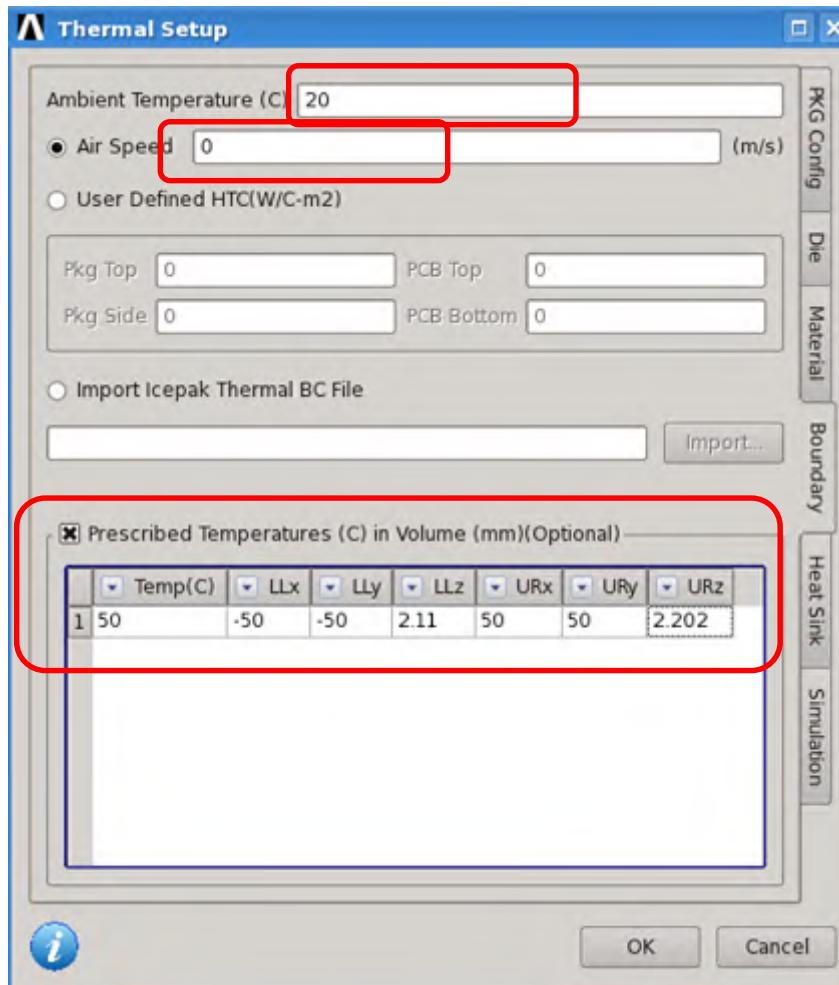


- For three die components, user needs to specify its CTM model or uniform power individually.
- If die adopts CTM power model, also specify its flip/Axis/rotation values to match package design and CTM power map

JEDEC Board Setting in RH-CTA

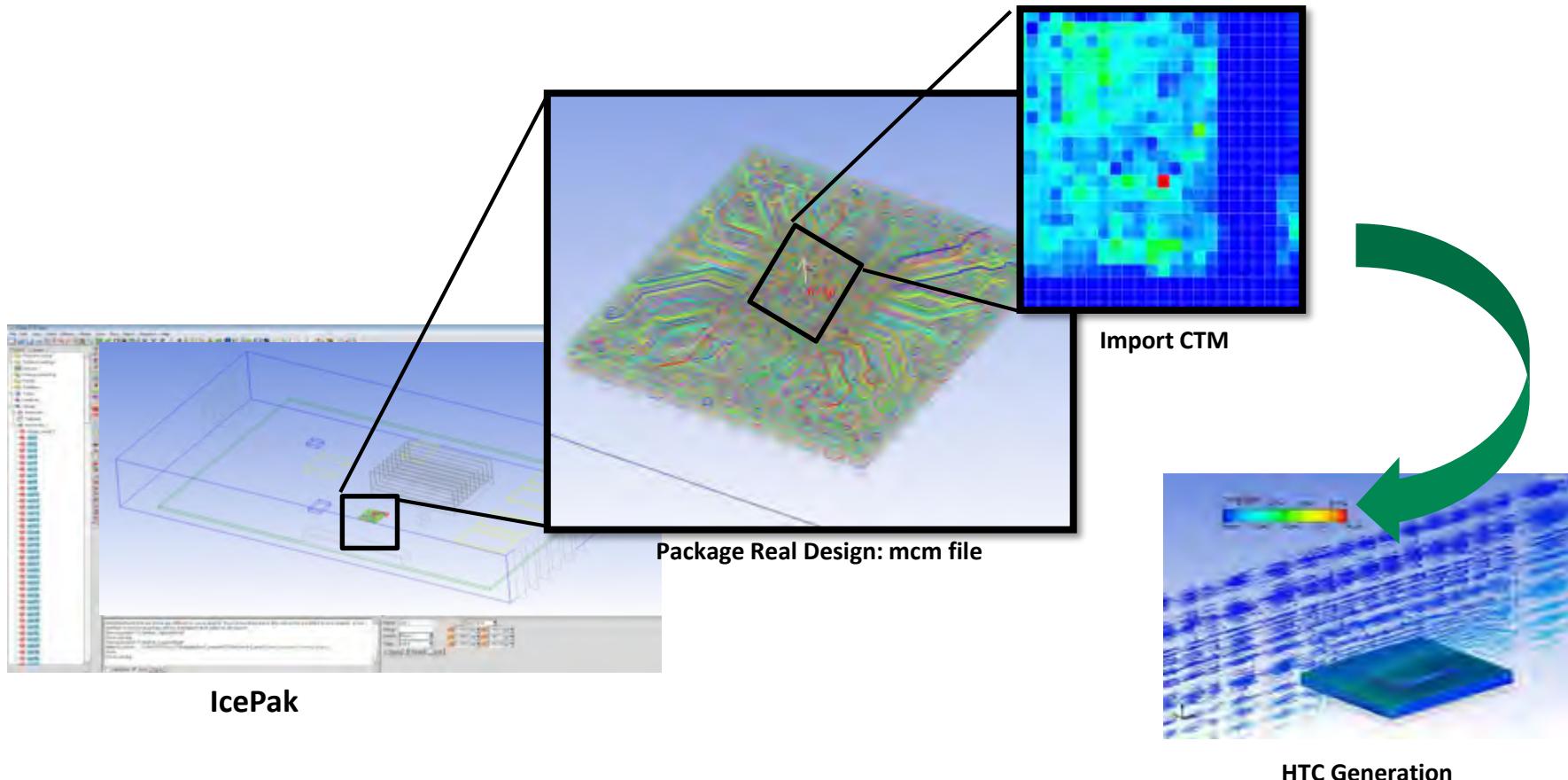


Thermal Boundary Condition(BC) Set up

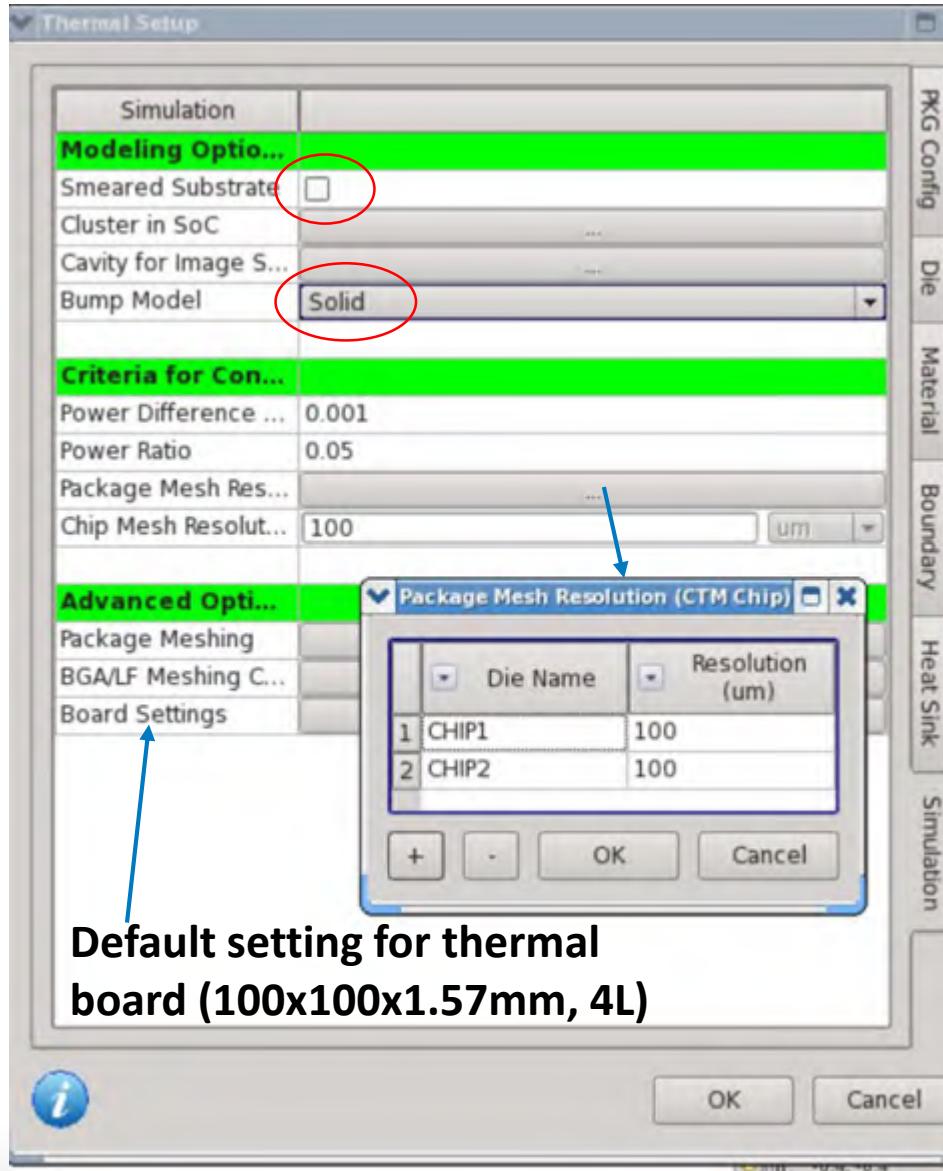


- Import HTC from IcePak or User-defined
- User-defined setup example
 - Specify env temperature; default 20C
 - Specify Air speed 0;
 - Specify prescribed temperature on top of DRAM

HTC Generation from IcePak



Simulation Configurations

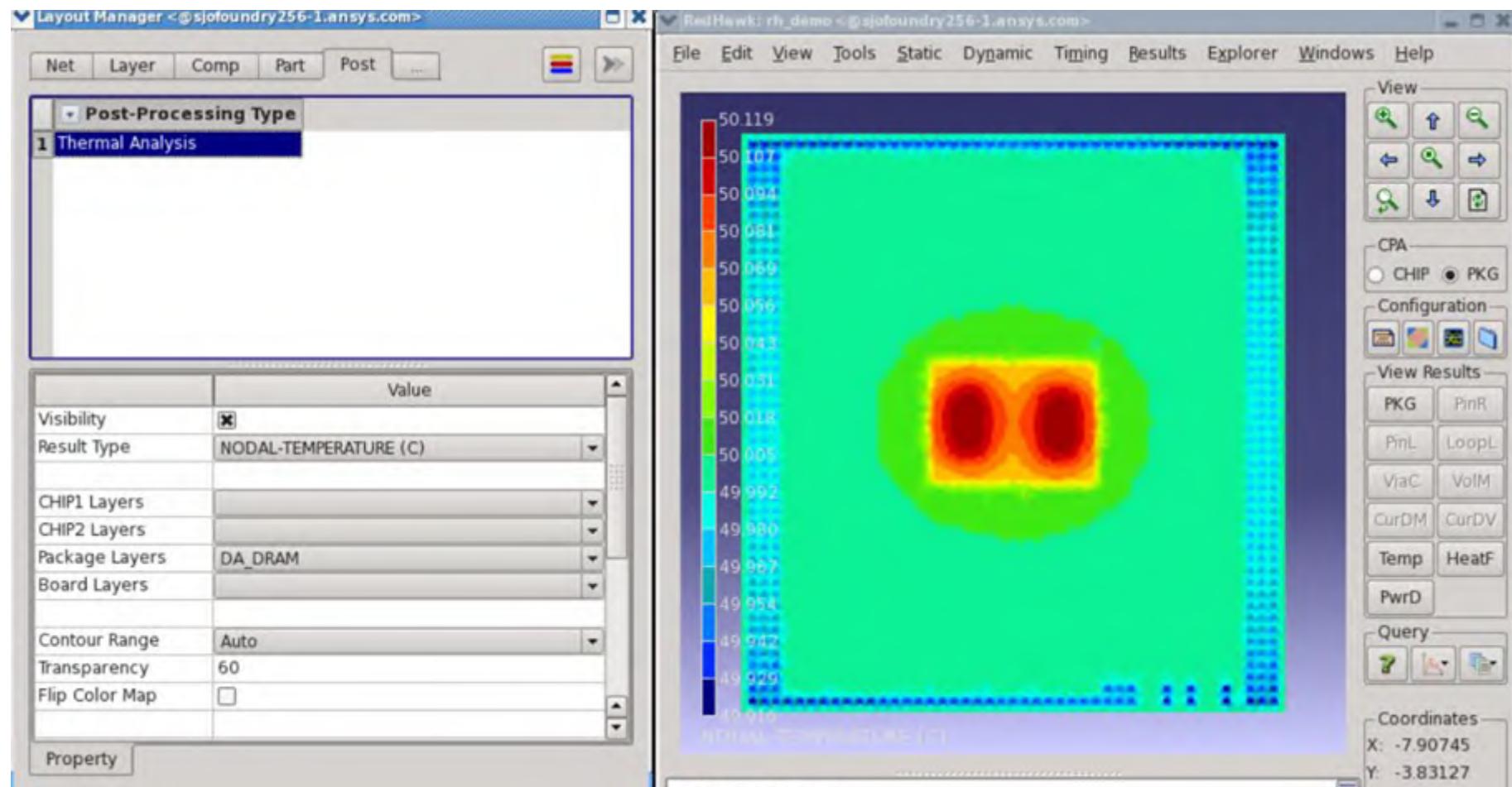


All layers modeled explicitly

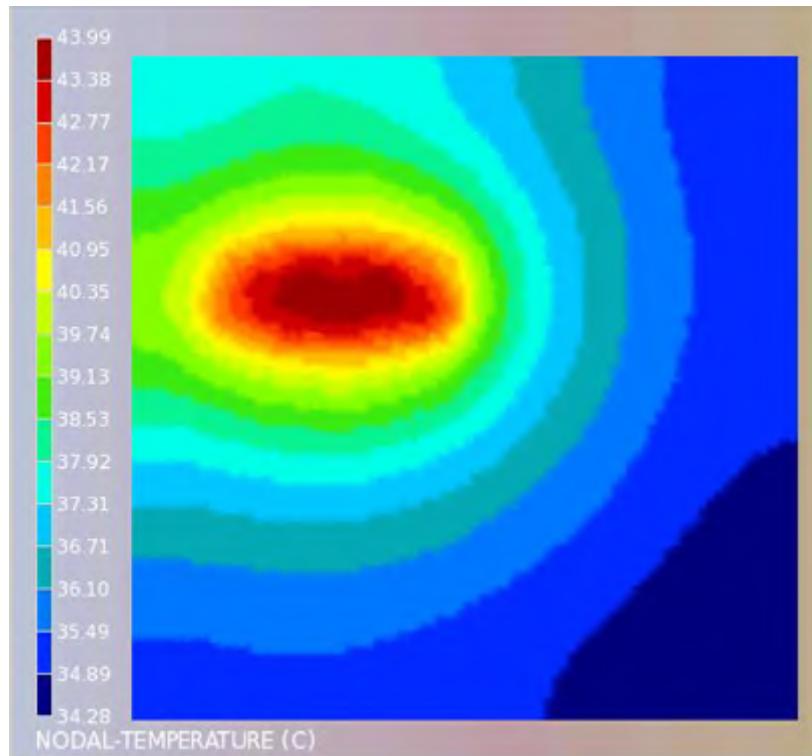
Solid elements for bumps/TIV

100um resolution for CTM dies

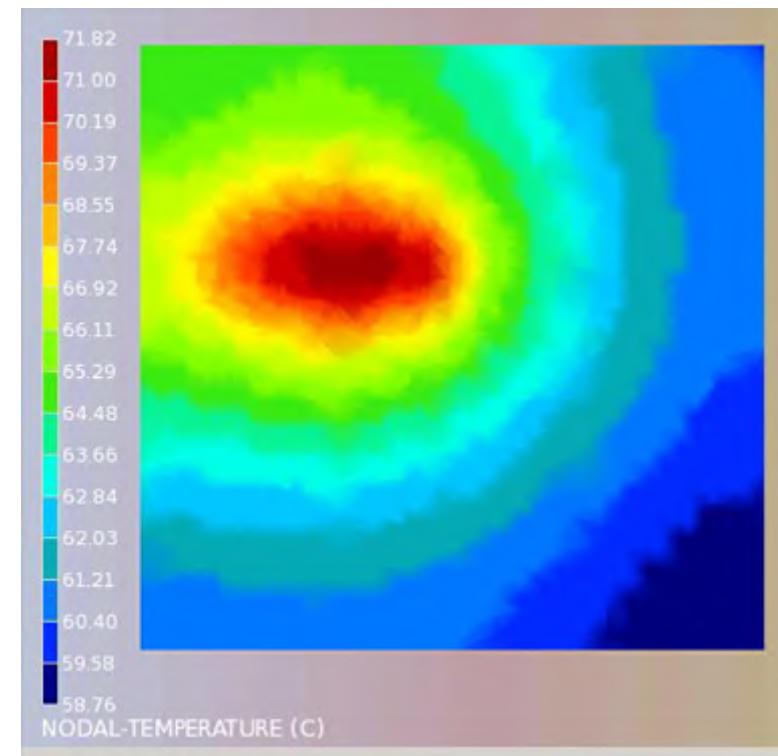
Thermal Analysis Results



Package Level Thermal Profile vs. Heat Source



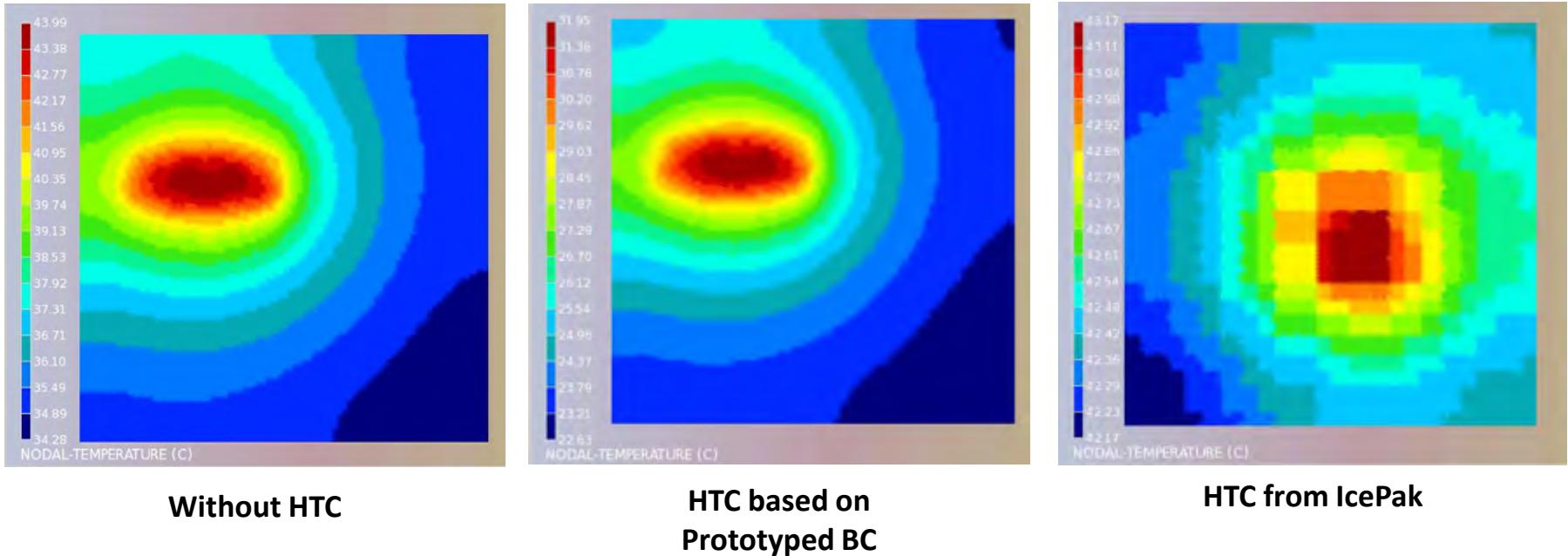
CTM(Chip Thermal Model)



30x30 Bin-based Power Map

- Wrong power map can lead to a wrong temperature result

Package Level Thermal Profile vs. HTC

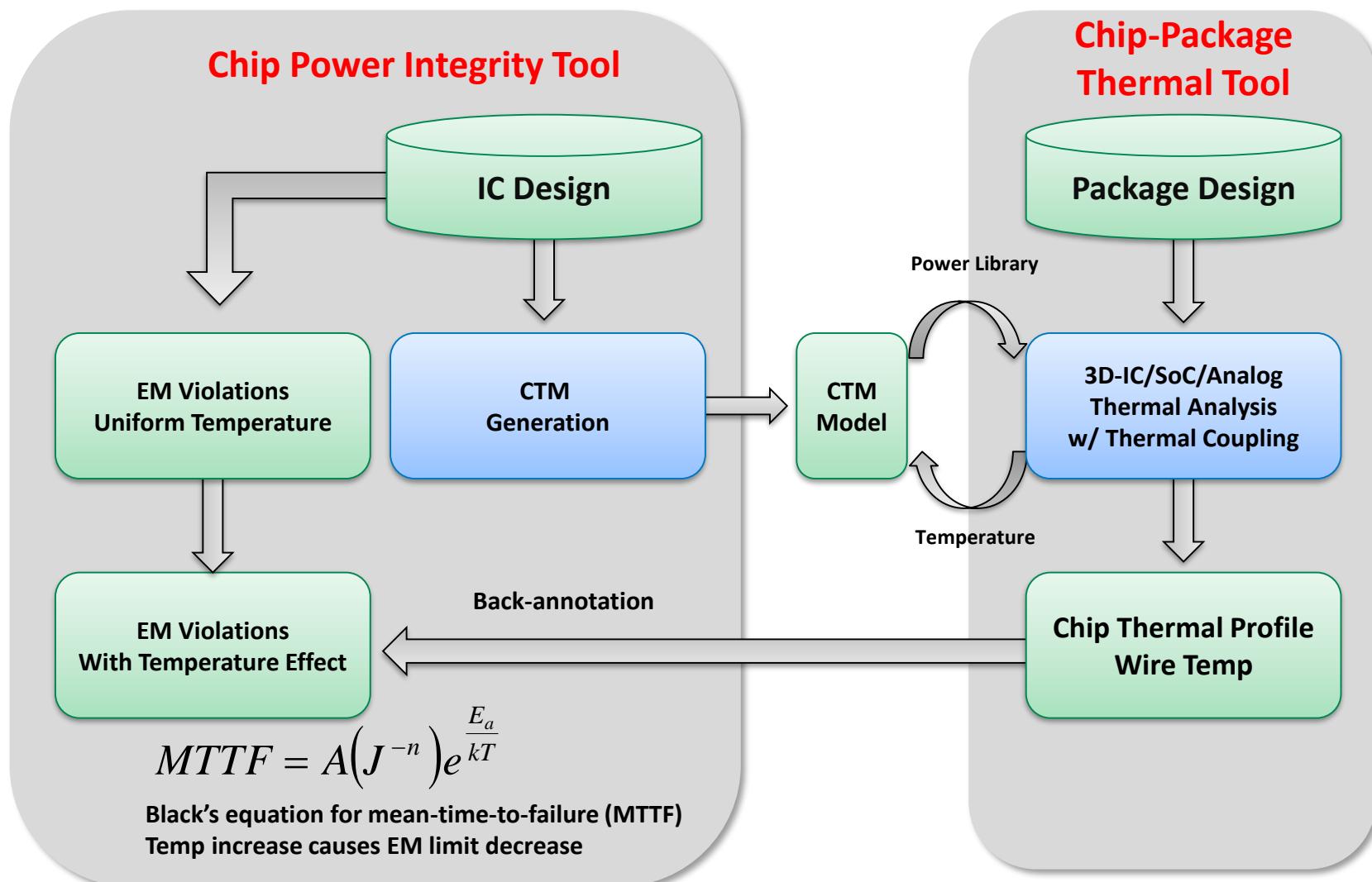


- **Hotspt and thermal profiles are different according to boundary condition and board design info**
- **CPS integrated solution is necessary for accuracy**

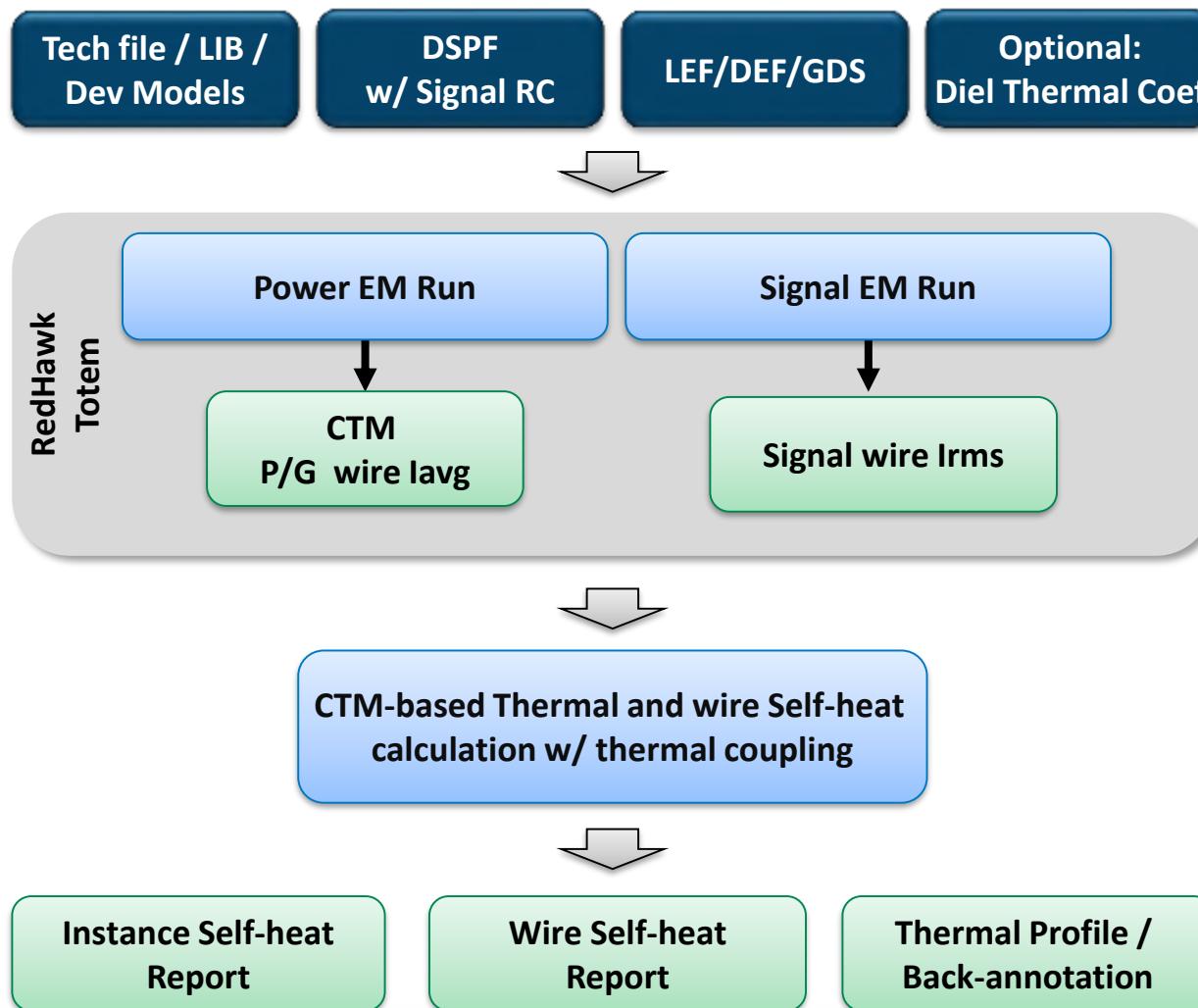
Demo Video

- **Should includes**
 - Design Set up for package level thermal analysis
 - CTM generation and import
 - Boundary condition and Jedec board setting
 - Thermal analysis and result show

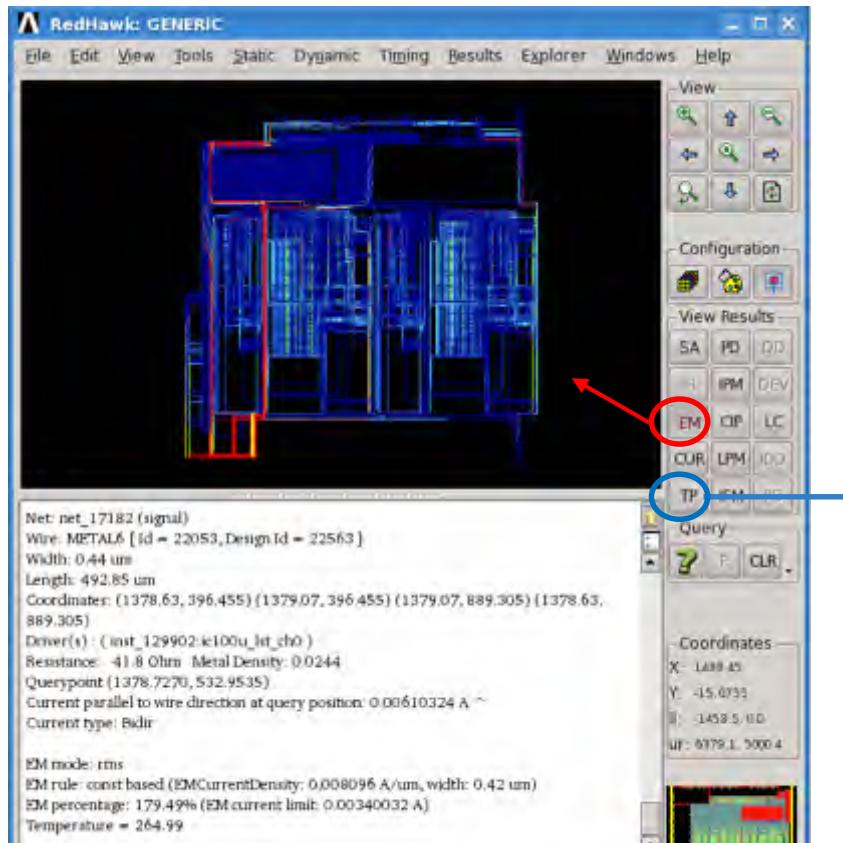
Chip-Package-System Thermal-Aware EM Flow



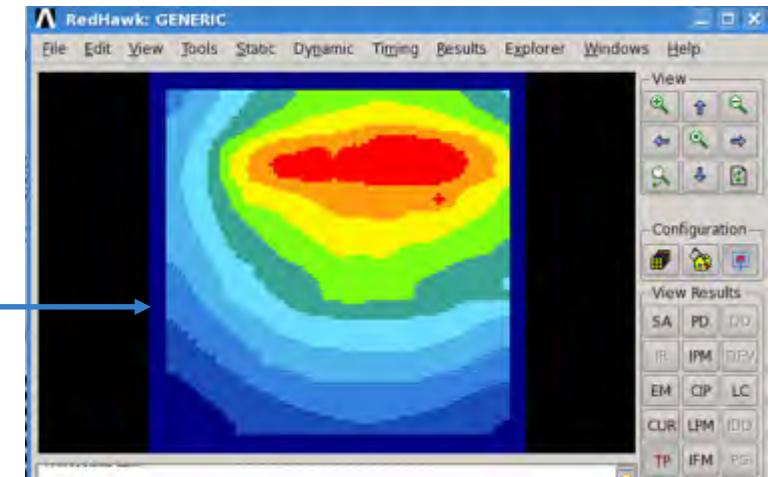
Self-heat Calculation Flow in RedHawk/Totem



RedHawk – View Thermal Maps



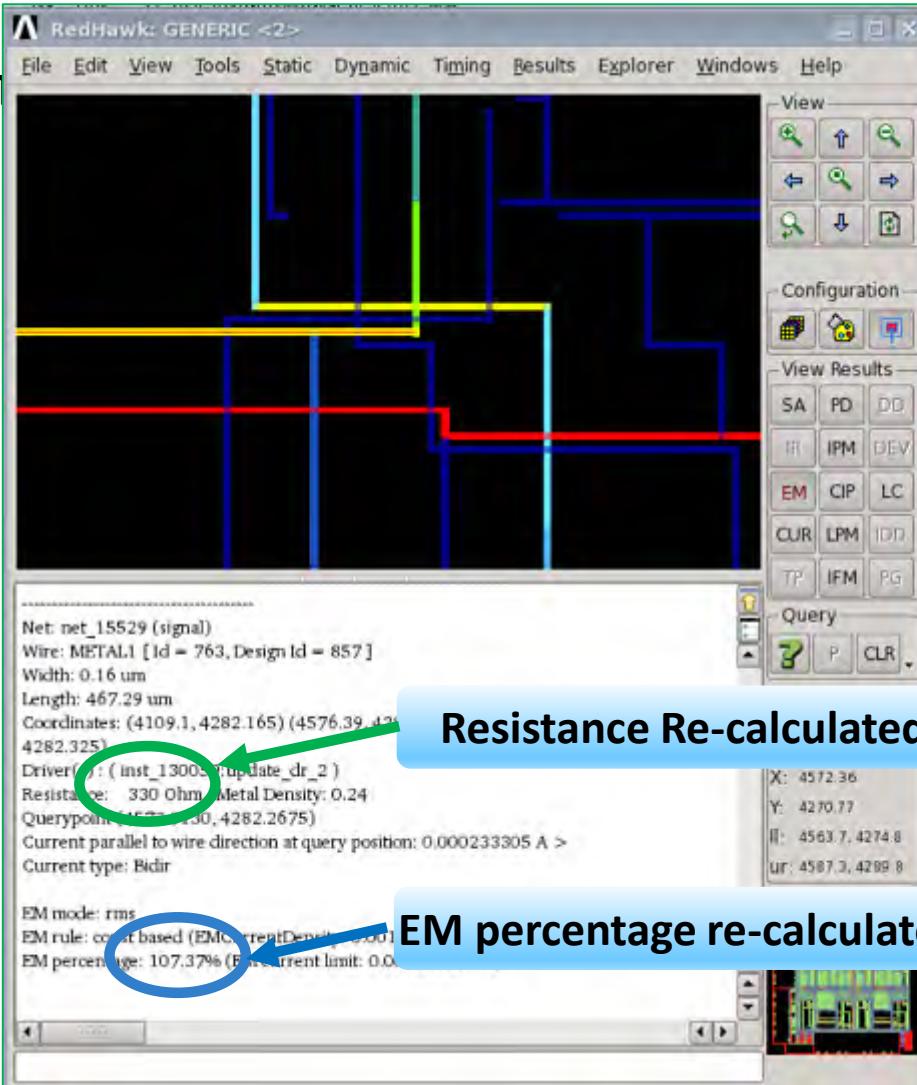
EM Color Maps



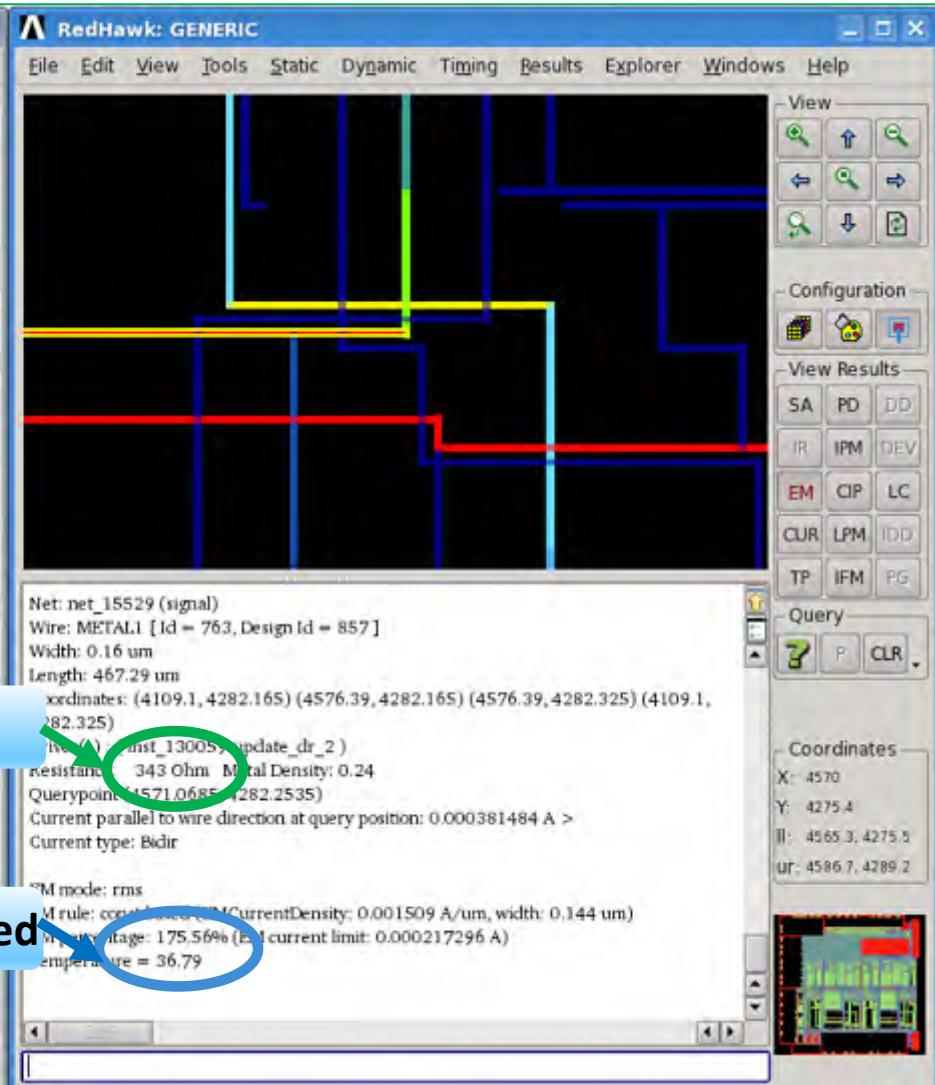
Tile-based temperature profile

- By layer EM color maps
- By layer temperature profile map

Redhawk Thermal-aware Resistance and EM vs. Package Design



Without Package Info



With Package Info

Demo Video

- Show EM analysis with thermal effect
- Compare the comparison data between normal EM and thermal-aware EM

ANSYS



仿真
新
时代

2017 ANSYS 用户技术大会

中国·烟台

感谢聆听

